

<b>Notice of References Cited</b>		Application/Control No. 10/601,899	Applicant(s)/Patent Under Reexamination WAN ET AL.	
		Examiner Nicholas T. La	Art Unit 2687	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,070,065	05-2000	Armbruster et al.	455/404.2
*	B	US-6,583,716	06-2003	Rangarajan et al.	340/7.56
*	C	US-6,438,376	08-2002	Elliott et al.	455/437
*	D	US-2002/0193121	12-2002	Nowak et al.	455/456
*	E	US-2004/0203867	10-2004	Schmidt, Karst	455/456.1
*	F	US-6,947,754	09-2005	Ogasawara, Koichi	455/456.3
*	G	US-2003/0186710	10-2003	Muhonen et al.	455/456.5
*	H	US-6,314,295	11-2001	Kawamoto, Yoji	455/456.2
*	I	US-2002/0107029	08-2002	Caughran et al.	455/456
*	J	US-6,909,902	06-2005	Sawada et al.	455/456.1
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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